FAIRCHILD

FDPF5N50NZU N-Channel UniFETTM II Ultra FRFETTM MOSFET 500 V, 3.9 A, 2.0 Ω

Features

- + $R_{DS(on)}$ = 1.7 Ω (Typ.) @ V_{GS} = 10 V, I_D = 1.95 A
- Low Gate Charge (Typ. 9 nC)
- Low C_{rss} (Typ. 4 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Imoroved Capability
- RoHS Compliant

Applications

- LCD/LED TV
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply

Description

UniFETTM II MOSFET is Fairchild Semiconductor[®]'s high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on-state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2kV HBM surge stress. UniFET II Ultra FRFETTM MOSFET has much superior body diode reverse recovery performance. Its trr is less than 50nsec and the reverse dv/dt immunity is 20V/nsec while normal planar MOSFETs have over 200nsec and 4.5V/nsec respectively. Therefore UniFET II Ultra FRFET MOSFET can remove additional component and improve system reliability in certain applications that require performance improvement of the MOSFET's body diode. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol	Parameter			FDPF5N50NZU	Unit	
V _{DSS}	Drain to Source Voltage			500	V	
V _{GSS}	Gate to Source Voltage	age		±25	V	
I _D	Droin Current	- Continuous ($T_C = 25^{\circ}C$) - Continuous ($T_C = 100^{\circ}C$)		3.9*	A	
	Drain Current			2.3*	A	
I _{DM}	Drain Current	- Pulsed (Note 1)		15*	A	
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	135	mJ	
I _{AR}	Avalanche Current		(Note 1)	3.9	A	
E _{AR}	Repetitive Avalanche Energy		(Note 1) 7.8		mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 1)	20	V/ns	
P _D	Dower Dissignation	$(T_{C} = 25^{\circ}C)$		30	W	
	Power Dissipation - Derate above 25°		°C	0.24	W/ºC	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C	
*Drain current lin	1/8" from Case for 5 Se					

Thermal Characteristics

Symbol	Parameter	FDPF5N50NZU	Unit	
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case, Max. 4.1		°C/W	
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	-0/10	

March 2013

Device MarkingDeviceFDPF5N50NZUFDPF5N50NZU		Device	Package	Reel Size	Таре	Width		Quantity	
		TO-220F			-		50		
Electrica	I Chai	racteristics T _c = 2	25ºC unless oth	erwise noted	-		I		
Symbol		Parameter		Test Conditions		Min.	Тур.	Max.	Unit
Off Charac	teristic	s							
BV _{DSS}	Drain te	o Source Breakdown Vo	Itage In	= 250µA, V _{GS} = 0V, T _C =	= 25°C	500	-	-	V
ΔBV _{DSS} ΔTJ	Breakd Coeffic	lown Voltage Temperatu ient	ro	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		-	0.5	-	V/ºC
	7	ero Gate Voltage Drain Current		V _{DS} = 500V, V _{GS} = 0V		-	-	25	μA
DSS	Zero G			$V_{DS} = 400V, V_{GS} = 0V, T_C = 125^{\circ}C$		-	-	250	
I _{GSS}	Gate to	Body Leakage Current	V	$V_{GS} = \pm 25V, V_{DS} = 0V$		-	-	±10	μA
On Charac	teristic	S							
V _{GS(th)}		hreshold Voltage	V	_{GS} = V _{DS} , I _D = 250μA		3.0	-	5.0	V
R _{DS(on)}		atic Drain to Source On Resistance		_{GS} = 10V, I _D = 1.95A		-	1.7	2.0	Ω
9 _{FS}	Forwar	orward Transconductance		$V_{\rm DS} = 20V, I_{\rm D} = 1.95A$			4.2	-	S
C _{iss} C _{oss} C _{rss}	Output	apacitance Capacitance e Transfer Capacitance		V _{DS} = 25V, V _{GS} = 0V f = 1MHz		-	365 50 4	485 65 8	pF pF pF
-		ate Charge at 10V		$V_{DS} = 400 V I_D = 3.9 A$ $V_{GS} = 10 V$ (Note 4)		-	9	12	nC
Q _{g(tot)} Q _{qs}		Source Gate Charge	v			_	2	-	nC
0		Drain "Miller" Charge					4		nC
Q _{gd}		C C				-	4	-	no
Switching	-								1
t _{d(on)}		n Delay Time			_	-	12	35	ns
t _r		n Rise Time		$V_{DD} = 250V, I_D = 3.9A$ $V_{GS} = 10V, R_{GEN} = 25\Omega$		-	19	50	ns
t _{d(off)}		ff Delay Time				-	31	70	ns
t _f	Turn-O	ff Fall Time			(Note 4)	-	22	55	ns
Drain-Sou	ce Dio	de Characteristics	5						
I _S	Maximu	Maximum Continuous Drain to Source Diode Forward Current				-	-	3.9	Α
I _{SM}	Maximu	Aximum Pulsed Drain to Source Diode For		rward Current		-	-	15	Α
V _{SD}	Drain to	o Source Diode Forward	Voltage V	_{GS} = 0V, I _{SD} = 3.9A		-	-	1.6	V
t _{rr}	Reverse	e Recovery Time	V	_{GS} = 0V, I _{SD} = 3.9A		-	45	-	ns
Q _{rr}	Reverse	e Recovery Charge	d	dl _F /dt = 100A/µs		-	33	-	nC

Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature

2. L = 18mH, I_{AS} = 3.9A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C

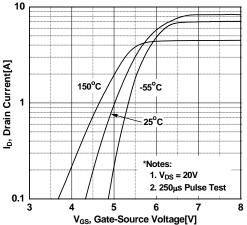
3. $I_{SD} \leq$ 3.9A, di/dt \leq 200A/µs, $V_{DD} \leq$ BV_{DSS}, Starting T_J = 25°C

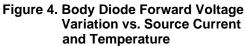
4. Essentially Independent of Operating Temperature Typical Characteristics

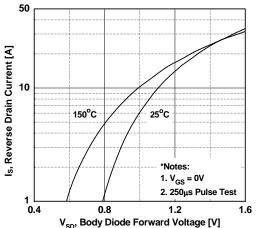


Typical Performance Characteristics Figure 1. On-Region Characteristics 10 V_{GS} = 15.0 V 10.0 V 8.0 V 7.0 V 6.5 V I_b, Drain Current[A] 6.0 V 1 5.5 V 5.0 V 0.1 Notes 1. 250µs Pulse Test 2. $T_{C} = 25^{\circ}C$ 0.03 25 10 0.1 1 V_{DS}, Drain-Source Voltage[V] Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage 3.6 R_{DS(ON)} [Ω], $V_{GS} = 10V$ $V_{GS} = 20V$ *Note: T_C = 25°C 1.2 0 2 4 6 8 10 I_D, Drain Current [A] **Figure 5. Capacitance Characteristics** 800 Ciss = Cgs + Cgd (Cds = shorted) Coss = Cds + Cgd V_{GS}, Gate-Source Voltage [V] Crss = Cgd 600 Capacitances [pF] Ciss 400 *Note: Coss 1. V_{GS} = 0V 2. f = 1MHz 200 Crss 0 0.1 1 10 30 V_{DS}, Drain-Source Voltage [V] ©2012 Fairchild Semiconductor Corporation 3 FDPF5N50NZU Rev. C0

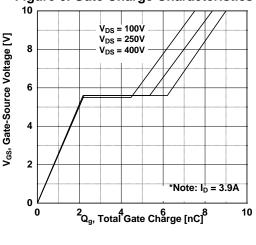
Figure 2. Transfer Characteristics

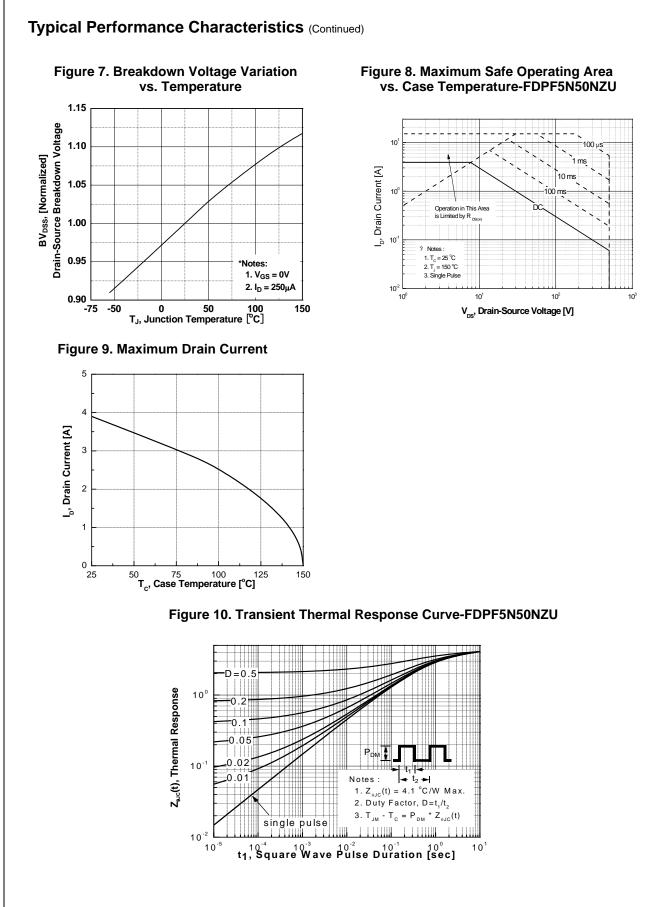


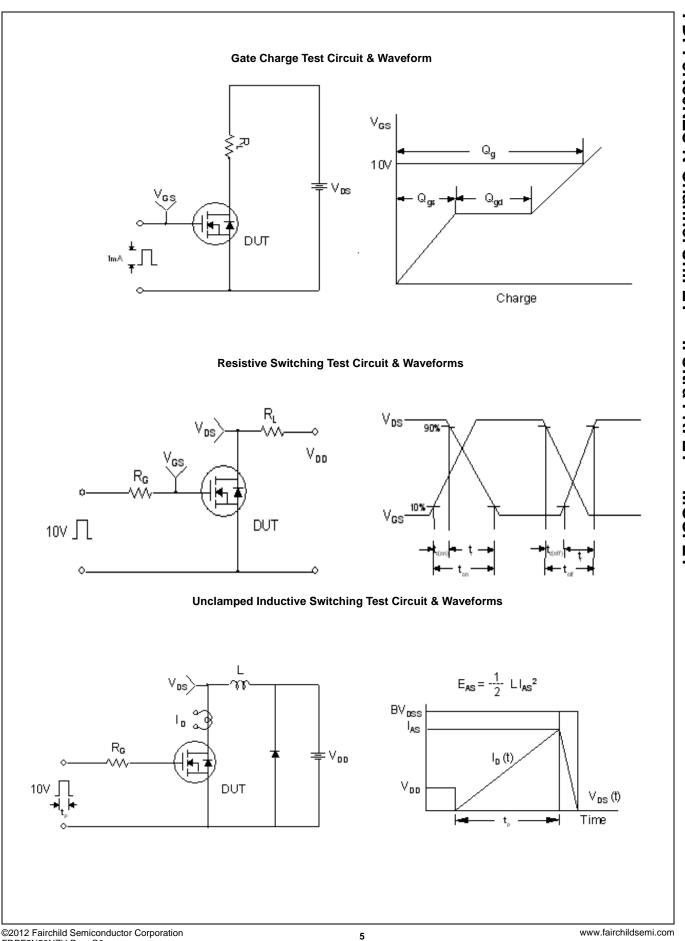




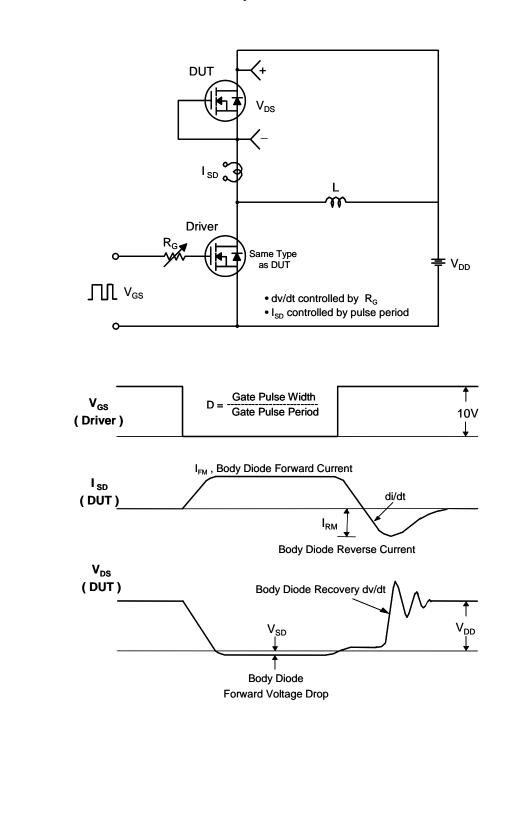


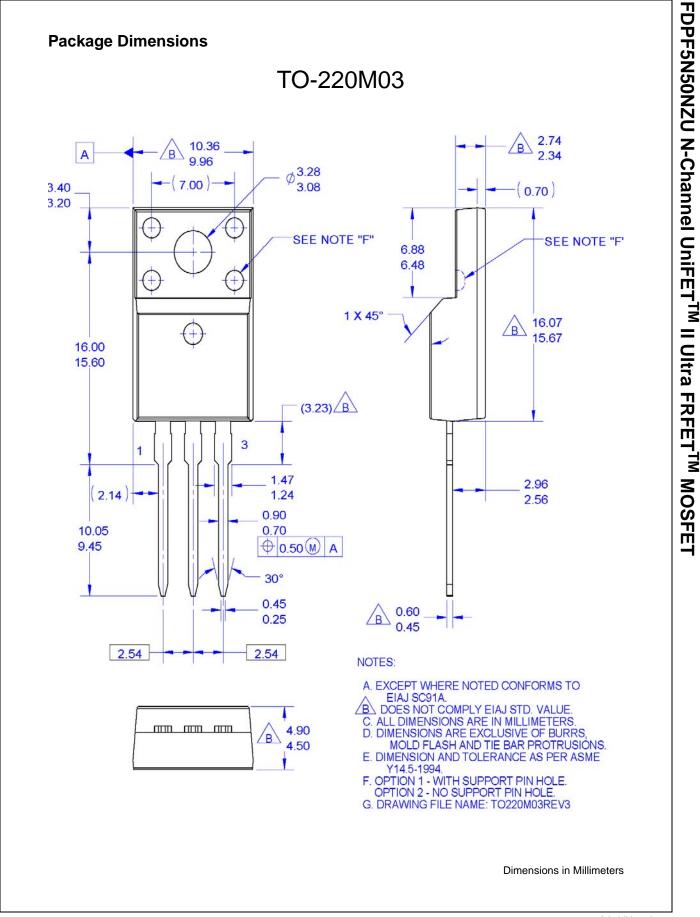






Peak Diode Recovery dv/dt Test Circuit & Waveforms







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